

08/10/04 TUE 12:24 FAX 281 834 1231

ECLT FORMALITIES BPC

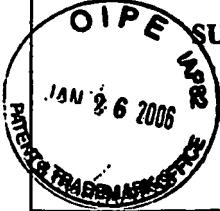
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FORM - 1449

SHEET 16 OF 35

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT <i>(Use several sheets if necessary)</i>			DOCKET NO.		SERIAL NO.		
			2003B043C		10/825,349		
			APPLICANT				
			Abhari et al.				
			FILED DATE	GROUP			
			April 15, 2004	1713			
FOREIGN PARENT DOCUMENTS							
		DOCUMENT NUMBER	TYPE DATE	COUNTRY	CLASS	ISUBCLASS	TRANSLATION
KW	MK	2001/0047064	01/29/01	Sun			
	ML	2001/0053837	12/20/01	Agarwal et al.			
	MM	2002/046054-0045054	04/18/02	Uhara et al.			
	MN	2002/049135-0049135	04/25/02	Moody et al.			
	MO	2002/061945-0061945	05/23/02	Oates et al.			
	MP	2002/064659-0064653	05/30/02	Ladika et al.			
	MQ	2002/065192-0065192	05/30/02	Mackenzie et al.			
	MR	2002/0010077	01/24/02	Lue et al.			
	MS	2002/0013440	01/31/02	Agarwal et al.			
	MT	2002/0016254	02/07/02	Whiteker et al.			
	MU	2002/0040114	04/04/02	Loveday et al.			
	MV	2002/0086955	07/04/02	Kendrick			
	MW	2002/432623-0132923	09/19/02	Langohr et al.			
	MX	2003/0096896	05/22/03	Wang et al.			
KW	MY	2004/0034170	02/19/04	Brant			
EXAMINER	/Katarzyna Wyrozebski Lee/			DATE CONSIDERED <u>10/25/2006</u>			

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next comment to applicant

 <p>SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT <i>(Use several sheets if necessary)</i></p>		ATTY. DOCKET NO.		SERIAL NO.			
		2003B043C		10/825,349			
		APPLICANT					
		Abhari, et al.					
		FILING DATE		GROUP			
		April 15, 2004		1713			
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
KW	AA	5,231,126	07-2-1993	Shi et al.	524	296	
	AB	6,747,114	06-08-2004	Karandinos, et al.	526	348.2	
	AC	6,774,069	08-10-2004	Zhou, et al.	442	328	
	AD	US 2002-0123538	09-05-2002	Zhou, et al.	523	176	
	AE	2003-078350 0078350	11-14-2002	Weng, et al.	526	160	04-23-2003
	AF	2004-048984 0048984	08-13-2003	Weng, et al.	525	245	03-11-2004
	AG	2004-0138392	10/15/2003	Jiang, et al.	526	114	07-15-2004
	AH	2004-127614 0127614	10/15/2003	Jiang, et al.	524	270	07-01-2004
	AI	2004-0220359	4/15/2004	Abhari, et al.	526	65	11-04-2004
▼	AJ	2004-0220336	4/15/2004	Abhari, et al.	525	70	11-04-2004
KW	AK	2004-0249046	4/15/2004	Abhari, et al.	524	474	12-09-2004
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	PUBL. DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
							YES
KW	AL	2316614	10-18-1973	DE			
	AM	1 295 926 A	03-26-2003	EP			
	AN	2407183	04-11-2003	CA			
	AO	02/36651 A	05-10-2002	WO			
▼	AP	2004/046214 A	06-03-2004	WO			
KW	AQ	2004/037872 A	05-06-2004	WO			
OTHER DISCLOSURES (Including Author, Title, Date, Pertinent Pages of Publication, Etc.)							
KW	AR	Abstract of DE 2316614					
KW	AS	Abstract of CA 2407183					
EXAMINER <i>/Katarzyna Wyrozebski Lee/</i>				DATE CONSIDERED <i>10/25/2006</i>			
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